N-channel TrenchMOS standard level FET Rev. 04 — 8 June 2010

**Product data sheet** 

#### **Product profile** 1.

### 1.1 General description

Standard level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology. This product has been designed and qualified to the appropriate AEC standard for use in automotive critical applications.

### 1.2 Features and benefits

- Low conduction losses due to low on-state resistance
- Q101 compliant

#### sources Suitable for thermally demanding

environments due to 175 °C rating

Suitable for standard level gate drive

- 1.3 Applications
  - 12 V loads
  - Automotive systems

- General purpose power switching
- Motors, lamps and solenoids

#### 1.4 Quick reference data

Table 1.	Quick reference data					
Symbol	Parameter	Conditions	Mir	тур	Max	Unit
V <sub>DS</sub>	drain-source voltage	T <sub>j</sub> ≥ 25 °C; T <sub>j</sub> ≤ 175 °C	-	-	30	V
I <sub>D</sub>	drain current	$V_{GS} = 10 \text{ V}; T_{mb} = 25 \text{ °C};$ see <u>Figure 1</u> ; see <u>Figure 3</u>	<u>[1]</u> _	-	75	A
P <sub>tot</sub>	total power dissipation	T <sub>mb</sub> = 25 °C; see Figure 2	-	-	300	W
Static cha	aracteristics					
R <sub>DSon</sub>	drain-source on-state resistance	$\label{eq:VGS} \begin{array}{l} V_{GS} = 10 \text{ V}; \text{ I}_{D} = 25 \text{ A}; \\ T_{j} = 25 \text{ °C}; \text{ see } \overline{Figure \ 11}; \\ \text{see } \overline{Figure \ 12} \end{array}$	-	2.3	2.7	mΩ
Avalanch	e ruggedness					
E <sub>DS(AL)S</sub>	non-repetitive drain-source avalanche energy	$ \begin{split} I_D &= 75 \text{ A};  \text{V}_{\text{sup}} \leq 30 \text{ V}; \\ R_{\text{GS}} &= 50  \Omega;  \text{V}_{\text{GS}} = 10  \text{V}; \\ T_{\text{j(init)}} &= 25 ^\circ\text{C}; \text{ unclamped} \end{split} $	-	-	2.3	J
Dynamic	characteristics					
Q <sub>GD</sub>	gate-drain charge	$V_{GS} = 10 \text{ V}; I_D = 25 \text{ A};$ $V_{DS} = 24 \text{ V}; T_j = 25 \text{ °C};$ see <u>Figure 13</u>	-	29	-	nC

[1] Continuous current is limited by package.



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### 2. Pinning information

Table 2.	Pinning	j information		
Pin	Symbol	Description	Simplified outline	Graphic symbol
1	G	gate		_
2	D	drain <sup>[1]</sup>	mb	
3	S	source		
mb	D	mounting base; connected to drain		mbb076 S
			SOT404 (D2PAK)	

[1] It is not possible to make connection to pin 2.

### 3. Ordering information

#### Table 3.Ordering information

Type number	Package		
	Name	Description	Version
BUK762R7-30B	D2PAK	plastic single-ended surface-mounted package (D2PAK); 3 leads (one lead cropped)	SOT404

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### 4. Limiting values

#### Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

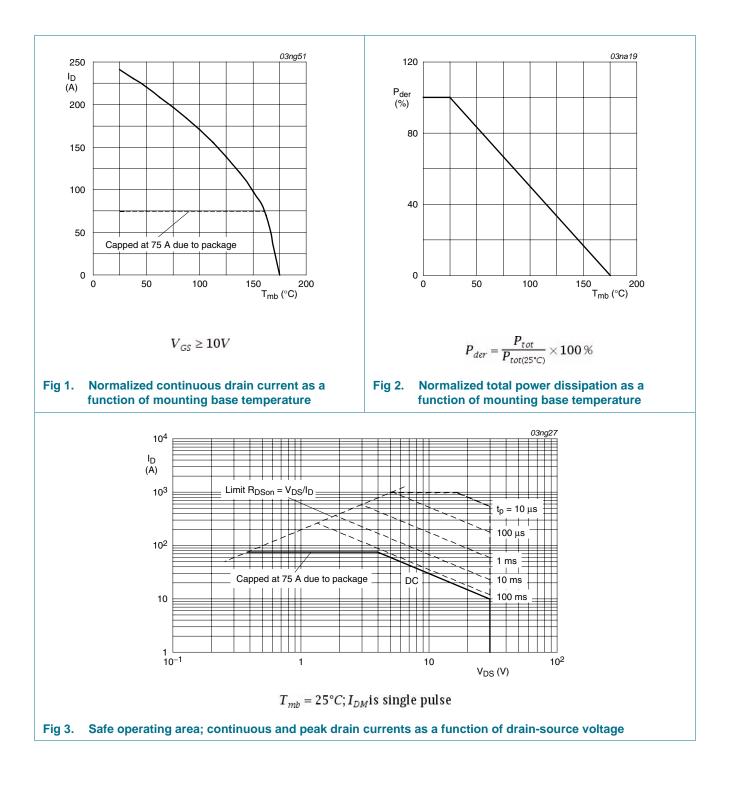
Symbol	Parameter	Conditions	Μ	lin	Тур	Max	Unit
V <sub>DS</sub>	drain-source voltage	T <sub>j</sub> ≥ 25 °C; T <sub>j</sub> ≤ 175 °C	-		-	30	V
V <sub>DGR</sub>	drain-gate voltage	$R_{GS}$ = 20 k $\Omega$	-		-	30	V
V <sub>GS</sub>	gate-source voltage		-2	20	-	20	V
I <sub>D</sub>	drain current	$T_{mb}$ = 25 °C; $V_{GS}$ = 10 V; see <u>Figure 1</u> ; see <u>Figure 3</u>	<u>[1]</u> _		-	241	А
		$T_{mb}$ = 100 °C; $V_{GS}$ = 10 V; see Figure 1	[2] _		-	75	А
		$T_{mb}$ = 25 °C; $V_{GS}$ = 10 V; see <u>Figure 1</u> ; see <u>Figure 3</u>	[2] _		-	75	А
I <sub>DM</sub>	peak drain current	T <sub>mb</sub> = 25 °C; t <sub>p</sub> ≤ 10 μs; pulsed; see <u>Figure 3</u>	-		-	967	A
P <sub>tot</sub>	total power dissipation	T <sub>mb</sub> = 25 °C; see <u>Figure 2</u>	-		-	300	W
T <sub>stg</sub>	storage temperature		-5	55	-	175	°C
Tj	junction temperature		-5	55	-	175	°C
Source-draii	n diode						
I <sub>S</sub>	source current	T <sub>mb</sub> = 25 °C	<u>[1]</u> _		-	241	А
			[2] _		-	75	А
I <sub>SM</sub>	peak source current	$t_p \le 10 \ \mu s$ ; pulsed; $T_{mb} = 25 \ ^{\circ}C$	-		-	967	А
Avalanche r	uggedness						
E <sub>DS(AL)S</sub>	non-repetitive drain-source avalanche energy	$I_D$ = 75 A; $V_{sup} \le 30$ V; $R_{GS}$ = 50 Ω; $V_{GS}$ = 10 V; $T_{j(init)}$ = 25 °C; unclamped	-		-	2.3	J

[1] Current is limited by power dissipation chip rating.

[2] Continuous current is limited by package.

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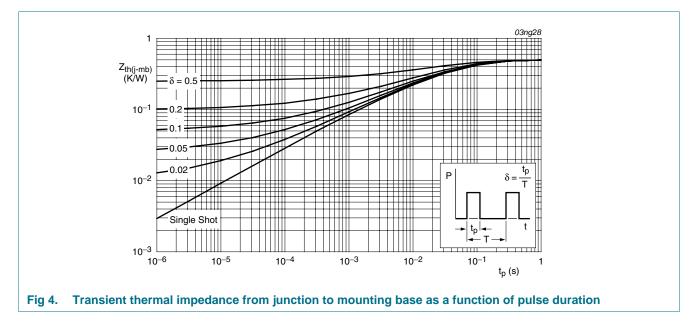
## BUK762R7-30B



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### 5. Thermal characteristics

Table 5.	Thermal characteristics					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
R <sub>th(j-mb)</sub>	thermal resistance from junction to mounting base	see Figure 4	-	-	0.5	K/W
R <sub>th(j-a)</sub>	thermal resistance from junction to ambient	minimum footprint ; mounted on a printed-circuit board	-	50	-	K/W

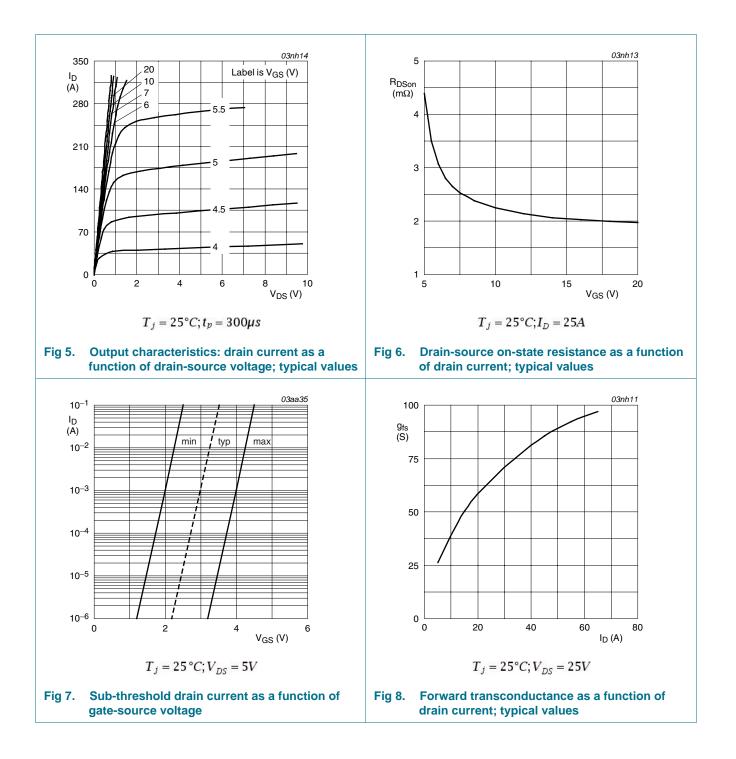


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### 6. Characteristics

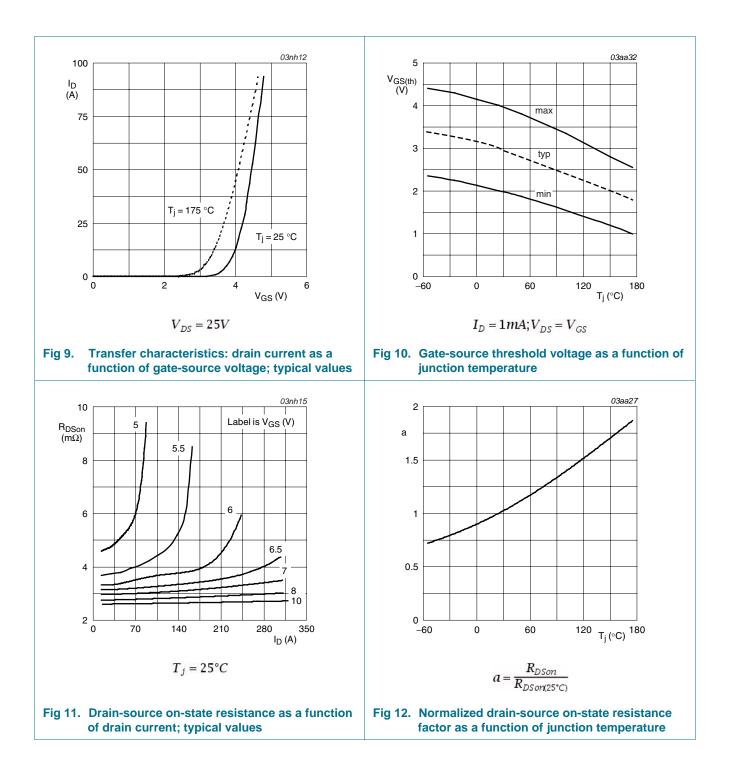
Table 6.	Characteristics					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	aracteristics					
V <sub>(BR)DSS</sub>	drain-source breakdown	$I_D = 0.25 \text{ mA};  V_{GS} = 0  \text{V};  T_j = 25 ^\circ\text{C}$	30	-	-	V
	voltage	$I_D$ = 0.25 mA; $V_{GS}$ = 0 V; $T_j$ = -55 °C	27	-	-	V
V <sub>GS(th)</sub>	gate-source threshold voltage	I <sub>D</sub> = 1 mA; V <sub>DS</sub> = V <sub>GS</sub> ; T <sub>j</sub> = 25 °C; see <u>Figure 10</u>	2	3	4	V
		$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = 175 \text{ °C};$ see Figure 10	1	-	-	V
		$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = -55 \text{ °C};$ see <u>Figure 10</u>	-	-	4.4	V
I <sub>DSS</sub>	drain leakage current	$V_{DS} = 30 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 175 \text{ °C}$	-	-	500	μA
		$V_{DS} = 30 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	0.02	1	μA
I <sub>GSS</sub>	gate leakage current	V <sub>DS</sub> = 0 V; V <sub>GS</sub> = 20 V; T <sub>j</sub> = 25 °C	-	2	100	nA
		$V_{DS} = 0 \text{ V}; V_{GS} = -20 \text{ V}; T_j = 25 \text{ °C}$	-	2	100	nA
R <sub>DSon</sub>	drain-source on-state resistance	$V_{GS}$ = 10 V; $I_D$ = 25 A; $T_j$ = 175 °C; see <u>Figure 11</u> ; see <u>Figure 12</u>	-	-	5.1	mΩ
		$V_{GS}$ = 10 V; $I_D$ = 25 A; $T_j$ = 25 °C; see <u>Figure 11</u> ; see <u>Figure 12</u>	-	2.3	2.7	mΩ
Dynamic	characteristics					
Q <sub>G(tot)</sub>	total gate charge	$I_D = 25 \text{ A}; V_{DS} = 24 \text{ V}; V_{GS} = 10 \text{ V};$	-	91	-	nC
Q <sub>GS</sub>	gate-source charge	T <sub>j</sub> = 25 °C; see <u>Figure 13</u>	-	19	-	nC
Q <sub>GD</sub>	gate-drain charge		-	29	-	nC
C <sub>iss</sub>	input capacitance	V <sub>GS</sub> = 0 V; V <sub>DS</sub> = 25 V; f = 1 MHz;	-	4659	6212	pF
C <sub>oss</sub>	output capacitance	T <sub>j</sub> = 25 °C; see <u>Figure 14</u>	-	1691	2029	pF
C <sub>rss</sub>	reverse transfer capacitance		-	622	852	pF
t <sub>d(on)</sub>	turn-on delay time	$V_{DS} = 30 \text{ V}; \text{ R}_{L} = 1.2 \Omega; \text{ V}_{GS} = 10 \text{ V};$	-	31	-	ns
t <sub>r</sub>	rise time	$R_{G(ext)} = 10 \ \Omega; T_j = 25 \ ^{\circ}C$	-	107	-	ns
t <sub>d(off)</sub>	turn-off delay time		-	113	-	ns
t <sub>f</sub>	fall time		-	118	-	ns
L <sub>D</sub>	internal drain inductance	from drain lead 6 mm from package to center of die ; $T_i = 25 \text{ °C}$	-	4.5	-	nH
		from upper edge of drain mounting base to centre of die ; $T_j = 25 \text{ °C}$	-	2.5	-	nH
L <sub>S</sub>	internal source inductance	from source lead to source bond pad ; $T_j = 25 \text{ °C}$	-	7.5	-	nH
Source-d	rain diode					
V <sub>SD</sub>	source-drain voltage	I <sub>S</sub> = 40 A; V <sub>GS</sub> = 0 V; T <sub>j</sub> = 25 °C; see <u>Figure 15</u>	-	0.85	1.2	V
t <sub>rr</sub>	reverse recovery time	I <sub>S</sub> = 20 A; dI <sub>S</sub> /dt = -100 A/μs;	-	88	-	ns
Q <sub>r</sub>	recovered charge	$V_{GS} = -10 \text{ V}; V_{DS} = 20 \text{ V}; T_j = 25 \text{ °C}$	-	132	-	nC

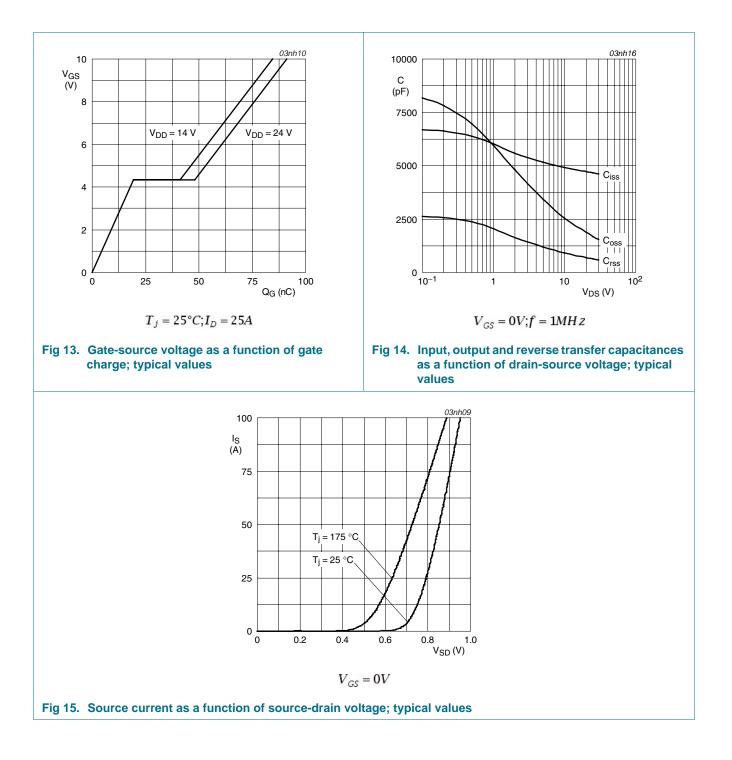
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### 7. Package outline

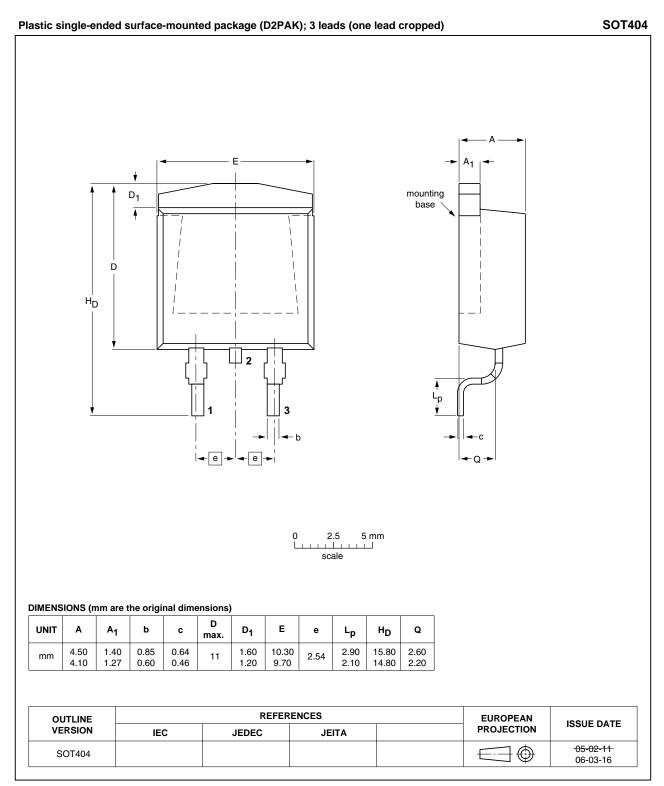


Fig 16. Package outline SOT404 (D2PAK)

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BUK762R7-30B

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### 8. Revision history

history	
Release date Data sheet status Change notice Supersedes	
20100608 Product data sheet - BUK75_76_7E2R7_30B	v.3
<ul> <li>The format of this data sheet has been redesigned to comply with the new ident guidelines of NXP Semiconductors.</li> </ul>	ity
<ul> <li>Legal texts have been adapted to the new company name where appropriate.</li> </ul>	
<ul> <li>Type number BUK762R7-30B separated from data sheet BUK75_76_7E2R7_30</li> </ul>	)B v.3.
0B v.3 20031013 Product data	
	20100608       Product data sheet       -       BUK75_76_7E2R7_30B         • The format of this data sheet has been redesigned to comply with the new ident guidelines of NXP Semiconductors.       •       Legal texts have been adapted to the new company name where appropriate.         • Type number BUK762R7-30B separated from data sheet BUK75_76_7E2R7_30B

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Document status[1][2]	Product status <sup>[3]</sup>	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
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